

100364 Low Power 16-Input Multiplexer

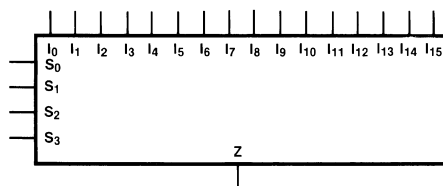
Check for Samples: [100364](#)

FEATURES

- 35% power reduction of the 100164
- 2000V ESD protection
- Pin/function compatible with 100164
- Voltage compensated operating range = -4.2V to -5.7V
- Available to industrial grade temperature range
- Standard Microcircuit Drawing
 - (SMD) 5962-9459201

DESCRIPTION

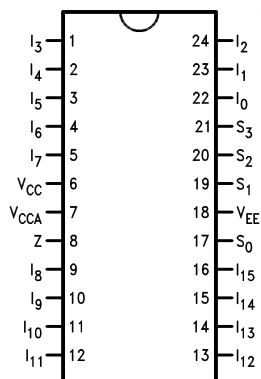
The 100364 is a 16-input multiplexer. Data paths are controlled by four Select lines (S_0 – S_3). Their decoding is shown in the truth table. Output data polarity is the same as the selected input data. All inputs have 50 k Ω pulldown resistors.



Pin Names	Description
I_0 – I_{15}	Data Inputs
S_0 – S_3	Select Inputs
Z	Data Output

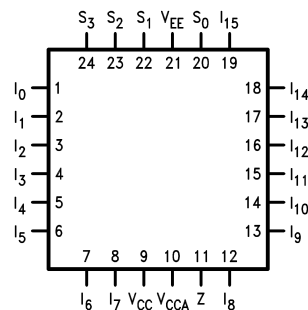
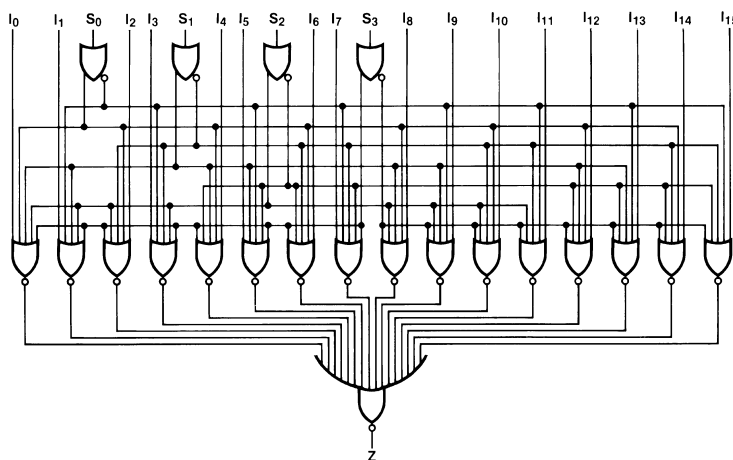
Connection Diagram

Figure 1. 24-Pin DIP



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Figure 2. 24-Pin Quad Cerpak**Logic Diagram****Truth Table**
(1)

Select Inputs				Output
S ₀	S ₁	S ₂	S ₃	Z
L	L	L	L	I ₀
H	L	L	L	I ₁
L	H	L	L	I ₂
H	H	L	L	I ₃
L	L	H	L	I ₄
H	L	H	L	I ₅
L	H	H	L	I ₆
H	H	H	L	I ₇
L	L	L	H	I ₈
H	L	L	H	I ₉
L	H	L	H	I ₁₀
H	H	L	H	I ₁₁
L	L	H	H	I ₁₂
H	L	H	H	I ₁₃
L	H	H	H	I ₁₄
H	H	H	H	I ₁₅

(1) H = HIGH Voltage Level
L = LOW Voltage Level



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

Absolute Maximum Ratings ⁽¹⁾

Above which the useful life may be impaired	
Storage Temperature (T_{STG})	-65°C to +150°C
Maximum Junction Temperature (T_J)	
Ceramic	+175°C
Pin Potential to	
Ground Pin (V_{EE})	-7.0V to +0.5V
Input Voltage (DC)	V_{EE} to +0.5V
Output Current	
(DC Output HIGH)	-50 mA
ESD ⁽²⁾	≥ 2000V

- (1) Absolute maximum ratings are those values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.
 (2) ESD testing conforms to MIL-STD-883, Method 3015.

Recommended Operating Conditions

Case Temperature (T_C)	
Military	-55°C to +125°C
Supply Voltage (V_{EE})	-5.7V to -4.2V

Military Version DC Electrical Characteristics

 $V_{EE} = -4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$, $T_C = -55^{\circ}C$ to $+125^{\circ}C$

Symbol	Parameter	Min	Max	Units	T_C	Conditions	Notes	
V_{OH}	Output HIGH Voltage	-1025	-870	mV	$0^{\circ}C$ to $+125^{\circ}C$	$V_{IN} = V_{IH}$ (Max) or V_{IL} (Min)	Loading with 50Ω to $-2.0V$	*(1) (2) (3)
		-1085	-870	mV	$-55^{\circ}C$			
V_{OL}	Output LOW Voltage	-1830	-1620	mV	$0^{\circ}C$ to $+125^{\circ}C$			
		-1830	-1555	mV	$-55^{\circ}C$			
V_{OHC}	Output HIGH Voltage	-1035		mV	$0^{\circ}C$ to $+125^{\circ}C$	$V_{IN} = V_{IH}$ (Min) or V_{IL} (Max)	Loading with 50Ω to $-2.0V$	(1) (2) (3)
		-1085		mV	$-55^{\circ}C$			
V_{OLC}	Output LOW Voltage		-1610	mV	$0^{\circ}C$ to $+125^{\circ}C$			
			-1555	mV	$-55^{\circ}C$			
V_{IH}	Input HIGH Voltage	-1165	-870	mV	$-55^{\circ}C$ to $+125^{\circ}C$	Guaranteed HIGH Signal for All Inputs	(1) (2) (3) (4)	
V_{IL}	Input LOW Voltage	-1830	-1475	mV	$-55^{\circ}C$ to $+125^{\circ}C$	Guaranteed LOW Signal for All Inputs	(1) (2) (3) (4)	
I_{IL}	Input LOW Current	0.50		μA	$-55^{\circ}C$ to $+125^{\circ}C$	$V_{EE} = -4.2V$ $V_{IN} = V_{IL}$ (Min)	(1) (2) (3)	
I_{IH}	Input HIGH Current		300	μA	$0^{\circ}C$ to $+125^{\circ}C$	$V_{EE} = -5.7V$ $V_{IN} = V_{IH}$ (Max)	(1) (2) (3)	
			450	μA	$-55^{\circ}C$			
I_{EE}	Power Supply Current	-95	-35	mA	$-55^{\circ}C$ to $+125^{\circ}C$	Inputs Open	(1) (2) (3)	

- (1) F100K 300 Series cold temperature testing is performed by temperature soaking (to guarantee junction temperature equals $-55^{\circ}C$), then testing immediately without allowing for the junction temperature to stabilize due to heat dissipation after power-up. This provides "cold start" specs which can be considered a worst case condition at cold temperatures.
- (2) Screen tested 100% on each device at $-55^{\circ}C$, $+25^{\circ}C$, and $+125^{\circ}C$, Subgroups, 1, 2, 3, 7 and 8.
- (3) Sampled tested (Method 5005, Table I) on each manufactured lot at $-55^{\circ}C$, $+25^{\circ}C$, and $+125^{\circ}C$, Subgroups A1, 2, 3, 7 and 8.
- (4) Guaranteed by applying specified input condition and testing V_{OH}/V_{OL} .

AC Electrical Characteristics

$V_{EE} = -4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$

Symbol	Parameter	$T_C = -55^\circ C$		$T_C = 25^\circ C$		$T_C = +125^\circ C$		Units	Conditions	Notes
		Min	Max	Min	Max	Min	Max			
t_{PLH} , t_{PHL}	Propagation Delay I_0 - I_{15} to Output	0.50	2.60	0.60	2.40	0.60	2.80	ns	Figure 3 Figure 4	*(1)(2)(3)
t_{PLH} , t_{PHL}	Propagation Delay S_0 , S_1 to Output	0.70	3.30	0.90	3.10	1.00	3.50	ns		
t_{PLH} , t_{PHL}	Propagation Delay S_2 , S_3 to Output	0.50	2.90	0.70	2.60	0.60	3.00	ns		
t_{TLH} , t_{THL}	Transition Time 20% to 80%, 80% to 20%	0.20	1.20	0.20	1.20	0.20	1.20	ns		(4)

- (1) F100K 300 Series cold temperature testing is performed by temperature soaking (to guarantee junction temperature equals $-55^\circ C$), then testing immediately without allowing for the junction temperature to stabilize due to heat dissipation after power-up. This provides "cold start" specs which can be considered a worst case condition at cold temperatures.
- (2) Screen tested 100% on each device at $+25^\circ C$, temperature only, Subgroup A9.
- (3) Sample tested (Method 5005, Table I) on each Mfg. lot at $+25^\circ C$, Subgroup A9, and at $+125^\circ C$, and $-55^\circ C$ temp., Subgroups A10 and A11.
- (4) Not tested at $+25^\circ C$, $+125^\circ C$ and $-55^\circ C$ temperature (design characterization data).

Test Circuit

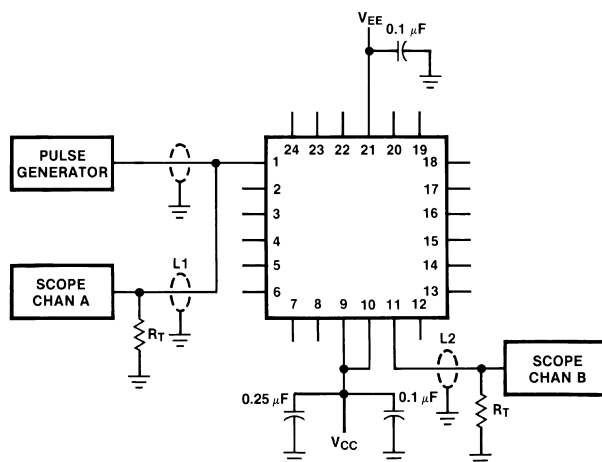
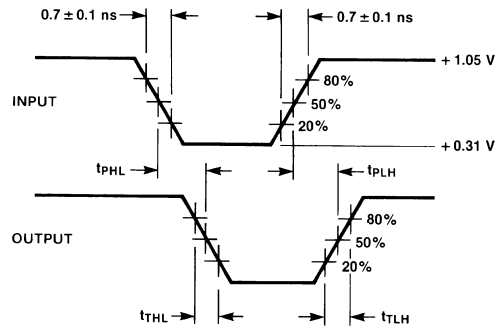


Figure 3. AC Test Circuit



$V_{CC}, V_{CCA} = +2V, V_{EE} = -2.5V$

L1 and L2 = Equal length 50Ω impedance lines

$R_T = 50\Omega$ terminator internal to scope

Decoupling 0.1 μF from GND to V_{CC} and V_{EE}

All unused outputs are loaded with 50Ω to GND

C_L = Fixture and stray capacitance ≤ 3 pF

Pin numbers shown are for flatpak; for DIP see logic symbol

Figure 4. Propagation Delay and Transition Times

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